



PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Abdurrahman Sezginer, et al.

Application No.: 10/613,378

Filed: July 3, 2003

For: OVERLAY METROLOGY METHOD  
AND APPARATUS USING MORE  
THAN ONE GRATING PER  
MEASUREMENT DIRECTION

Confirmation No.: 7200

Group Art Unit: 2877

Examiner: Gordon J. Stock, Jr.

**RESPONSE TO OFFICE ACTION  
MAILED JUNE 7, 2005**

353 Sacramento St., Suite 2200  
San Francisco, CA 94111  
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**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope, addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on August 23, 2005.  
STALLMAN & POLLOCK LLP

Dated: 08/23/2005 By: Georgia K. Stith  
Georgia K. Stith

M/S AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the Office Action mailed June 7, 2005, please amend the above-identified application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 4 of this paper.

**Amendments to the Drawings** begin on page 6 of this paper and include an attached replacement sheet.

**Remarks/Arguments** begin on page 7 of this paper.

Atty Docket No.: TTI-32410